

List of publications

Refereed papers: 133

Proceedings: 22

Review articles: 20

Books: 3 (co-authored)

1. Thesis

"Rapid diffusion and surface segregation in metallic films"

April 1992(PhD), Tokyo University

2. Refereed original papers

- Modification of terminating species and band alignment at the interface between alumina films and metal single crystals, **M. Yoshitake**, S. Nemsák, T. Skála, N. Tsud, T. Kim, V. Matolín, K. C. Prince, Surf.Sci. 604, 2150-2156 (2010).
- A photoelectron spectroscopy study of ultra-thin epitaxial alumina layers grown on Cu(111) surface S. Nemsák, T Skála, **M. Yoshitake**, N. Tsud, K. C. Prince, , V. Matolín, Surf.Sci. 604, 2073-2077 (2010).
- XPS Study on Band Alignment at Pt-O-terminated ZnO(000_1) Interface, T. Kim, **M. Yoshitake**, S. Yagyu, S. Nemsák, T Nagata, T. Chikyow, Surf.Interface Anal., 2010, 42, 1528–1531
- Growth of thin epitaxial alumina films onto Ni(111): an electron spectroscopy and diffraction study, S. Nemsák, T Skála, **M. Yoshitake**, N. Tsud, T. Kim, S. Yagyu, V. Matolín, Surf. Interface Anal. 2010, 42, 1589–1592
- Schottky barrier height behavior of Pt–Ru alloy contacts on single-crystal n-ZnO, T. Nagata, J. Volk, M. Haemori, Y. Yamashita, H. Yoshikawa, R. Hayakawa, **M. Yoshitake**, S. Ueda, K. Kobayashi, and T. Chikyow, J. Appl. Phys. 107, 103714 (2010).
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- Low pressure oxidation of ordered Sn/Pd(110) surface alloys, N Tsud, T Skála, F Šutara, K.Veltruská, V Dudr, **M. Yoshitake**, K C Prince and V Matolín, J. Phys.: Condens. Matter 21 (2009) 185011-1-9
- Interface structure and the chemical states of Pt film on polar-ZnO single crystal, T.Nagata, J. Volk, Y.Yamashita, H.Yoshikawa, M.Haemori, R.Hayakawa, **M. Yoshitake**, S.Ueda, K.Kobayashi, T.Chikyow, Appl.Phys.Lett. 94, 221904-1-221904-3, (2009)
- Adsorption structure of phenylphosphonic acid on alumina surface, S.Yagyu, **M. Yoshitake**, N.Tsud, T. Chikyow, Appl.Surf.Sci., 256, 1140-1143(2009)

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